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Development of fast, monolithic silicon pixel sensors in a SiGe Bi-CMOS process.

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An ultra-fast, low-noise and low-power SiGe Bi-CMOS electronics was developed and implemented in a monolithic silicon pixel sensors, with the aim to achieve 100ps time resolution for minimum ionising particles with 500x500 micron² pixels, corresponding to ⁷⁵⁰fF capacity. The performance of a prototype chip, comprising a 3x10 pixel matrix and a 50ps binning TDC will be shown, together with the technique proposed to synchronise a large number of sensors at picosecond level.

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